

Notice of References Cited	Application/Control No. 10/762,526		Applicant(s)/Patent Under Reexamination CHOI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,376,692	03-1983	Tsukada et al.	204/298.31
*	B	US-5,413,673	05-1995	Fujimoto, Hideki	156/345.47
*	C	US-5,707,485	01-1998	Rolfson et al.	438/716
*	D	US-5,919,332	07-1999	Koshiishi et al.	156/345.47
*	E	US-5,959,409	09-1999	Dornfest et al.	315/111.21
*	F	US-6,333,601 B1	12-2001	Wickramanayaka, Sunil	315/111.41
*	G	US-6,553,932 B2	04-2003	Liu et al.	118/723E
*	H	US-6,837,967 B1	01-2005	Berman et al.	156/345.3
*	I	US-6,887,340 B2	05-2005	Dhindsa et al.	156/345.3
*	J	US-2002/0170676 A1	11-2002	Mitrovic et al.	156/345.47
*	K	US-2003/0070760 A1	04-2003	Kim et al.	156/345.43
*	L	US-2003/0150562 A1	08-2003	Quon, Bill H.	156/345.47
*	M	US-2003/0201069 A1	10-2003	Johnson, Wayne L.	156/345.43

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0137745 A1	07-2004	Houghton et al.	438/706
*	B	US-2004/0238488 A1	12-2004	Choi et al.	216/058
*	C	US-2005/0061445 A1	03-2005	Koshiishi et al.	156/345.47
*	D	US-2005/0079729 A1	04-2005	Jang, Woo-Sung	438/758
*	E	US-2005/0098111 A1	05-2005	Shimizu et al.	118/715
*	F	US-2005/0103442 A1	05-2005	Chen et al.	156/345.47
*	G	US-2005/0269292 A1	12-2005	Koshiishi et al.	216/067
*	H	US-2006/0048894 A1	03-2006	Yamazaki et al.	156/345.45
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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